Excellent Integrated System Limited

Stocking Distributor

Click to view price, real time Inventory, Delivery & Lifecycle Information:

Fairchild Semiconductor FDC6302P

For any questions, you can email us directly: sales@integrated-circuit.com

Distributor of Fairchild Semiconductor: Excellent Integrated System Limited

Datasheet of FDC6302P - MOSFET 2P-CH 25V 0.12A SSOT6

Contact us: sales@integrated-circuit.com Website: www.integrated-circuit.com



October 1997

FDC6302P Digital FET, Dual P-Channel

General Description

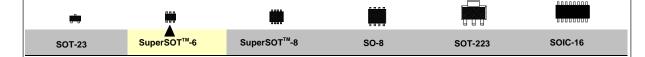
These Dual P-Channel logic level enhancement mode field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. This device has been designed especially for low voltage applications as a replacement for digital transistors in load switching applications. Since bias resistors are not required this one P-Channel FET can replace several digital transistors with different bias resistors like the IMBxA series.

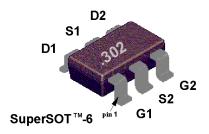
Features

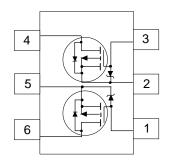
-25 V, -0.12 A continuous, -0.5 A Peak.

$$\begin{split} R_{\text{DS(ON)}} &= 13~\Omega~@~V_{\text{GS}} \text{= -2.7 V} \\ R_{\text{DS(ON)}} &= 10~\Omega~@~V_{\text{GS}} \text{= -4.5 V}. \end{split}$$

- Very low level gate drive requirements allowing direct operation in 3V circuits. V_{GS(th)} < 1.5V.
- Gate-Source Zener for ESD ruggedness.
 >6kV Human Body Model
- Replace multiple PNP digital transistors (IMHxA series) with one DMOS FET.







Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless other wise noted

| Symbol | Parameter | | FDC6302P | Units | |
|-------------------|--|-----------|------------|-------|--|
| V _{DSS} | Drain-Source Voltage | | -25 | V | |
| V_{GSS} | Gate-Source Voltage | | -8 | V | |
| D | Drain Current - Continuous | | -0.12 | А | |
| | - Pulsed | | -0.5 | | |
| P_{D} | Maximum Power Dissipation | (Note 1a) | 0.9 | W | |
| | | (Note 1b) | 0.7 | | |
| T_J , T_{STG} | Operating and Storage Temperature Range | | -55 to 150 | °C | |
| ESD | Electrostatic Discharge Rating MIL-STD-883D Human Body Model (100pf / 1500 Ohm) | | 6.0 | kV | |
| THERMA | L CHARACTERISTICS | · | | · | |
| R _{eJA} | Thermal Resistance, Junction-to-Ambient | (Note 1a) | 140 | °C/W | |
| R _{euc} | Thermal Resistance, Junction-to-Case | (Note 1) | 60 | °C/W | |



Distributor of Fairchild Semiconductor: Excellent Integrated System Limited

Contact us: sales@integrated-circuit.com Website: www.integrated-circuit.com

Datasheet of FDC6302P - MOSFET 2P-CH 25V 0.12A SSOT6

| Symbol | Parameter | Conditions | Min | Тур | Max | Units |
|----------------------------------|---|--|-------|-------|------|--------|
| OFF CHAR | ACTERISTICS | · | • | • | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0 \text{ V}, \ I_{D} = -250 \mu\text{A}$ | -25 | | | V |
| $\Delta BV_{DSS}/\Delta T_{J}$ | Breakdown Voltage Temp. Coefficient | I_D = -250 μ A, Referenced to 25 $^{\circ}$ C | | -20 | | mV /°C |
| DSS | Zero Gate Voltage Drain Current | $V_{DS} = -20 \text{ V}, \ V_{GS} = 0 \text{ V}$ | | | -1 | μA |
| | | T _J = 55°C | | | -10 | μA |
| GSS | Gate - Body Leakage Current | $V_{GS} = -8 \text{ V}, \ V_{DS} = 0 \text{ V}$ | | | -100 | nA |
| ON CHARAC | CTERISTICS (Note 2) | | • | • | | • |
| $\Delta V_{GS(th)}/\Delta T_{J}$ | Gate Threshold Voltage Temp. Coefficient | I_D = -250 μ A, Referenced to 25 $^{\circ}$ C | | 1.9 | | mV /°C |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$ | -0.65 | -1 | -1.5 | V |
| R _{DS(ON)} | Static Drain-Source On-Resistance | $V_{GS} = -2.7 \text{ V}, I_{D} = -0.05 \text{A}$ | | 10.6 | 13 | Ω |
| | | $V_{GS} = -4.5 \text{ V}, I_D = -0.2 \text{ A}$ | | 7.9 | 10 | |
| | | T _J =125°C | | 12 | 18 | |
| D(ON) | On-State Drain Current | $V_{GS} = -2.7 \text{ V}, \ V_{DS} = -5 \text{ V}$ | -0.05 | | | Α |
| 9 _{FS} | Forward Transconductance | $V_{DS} = -5 \text{ V}, I_{D} = -0.2 \text{ A}$ | | 0.135 | | S |
| DYNAMIC C | HARACTERISTICS | | | | | |
| C _{iss} | Input Capacitance | $V_{DS} = -10 \text{ V}, \ V_{GS} = 0 \text{ V},$ f = 1.0 MHz | | 11 | | pF |
| Coss | Output Capacitance | f = 1.0 MHz | | 7 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 1.4 | | pF |
| SWITCHING | CHARACTERISTICS (Note 2) | | | | | |
| D(on) | Turn - On Delay Time | $V_{DD} = -6 \text{ V}, I_{D} = -0.2 \text{ A},$ | | 5 | 12 | ns |
| r | Turn - On Rise Time | $V_{GS} = -4.5 \text{ V}, \ R_{GEN} = 50 \Omega$ | | 8 | 16 | ns |
| D(off) | Turn - Off Delay Time | | | 9 | 18 | ns |
| f | Turn - Off Fall Time | | | 5 | 10 | ns |
| Q_g | Total Gate Charge | $V_{DS} = -5 \text{ V}, I_{D} = -0.2 \text{ A},$ | | 0.22 | 0.31 | nC |
| Q_{gs} | Gate-Source Charge | V _{GS} = -4.5 V | | 0.12 | | nC |
| Q_{gd} | Gate-Drain Charge | | | 0.05 | | nC |
| DRAIN-SOU | RCE DIODE CHARACTERISTICS AND MAX | KIMUM RATINGS | | 1 | | |
| s | Maximum Continuous Drain-Source Diode Forward Current | | | | -0.7 | Α |
| V_{SD} | Drain-Source Diode Forward Voltage | $V_{GS} = 0 \text{ V}, I_{S} = -0.7 \text{ A} \text{ (Note 2)}$ | | -1 | -1.3 | V |

Notes:
1. R_{u.k.} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{u.k.} is guaranteed by design while R_{bc.k.} is determined by the user's board design.



a. 140°C/W on a 0.125 in² pad of 2oz copper.



b. 180°C/W on a 0.005 in² of pad of 2oz copper.

2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%.

Typical Electrical Characteristics

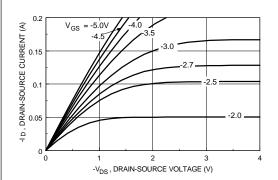


Figure 1. On-Region Characteristics.

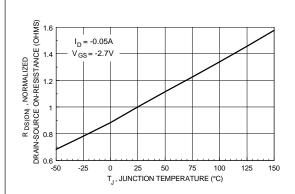


Figure 3. On-Resistance Variation with Temperature.

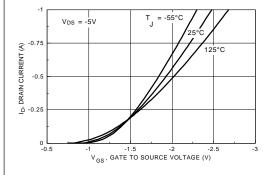


Figure 5. Transfer Characteristics.

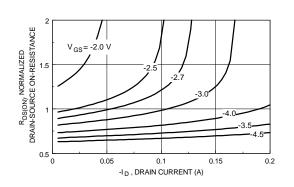


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

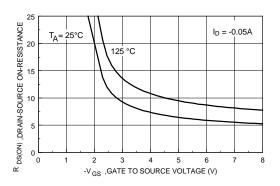


Figure 4. On Resistance Variation with Gate-To- Source Voltage.

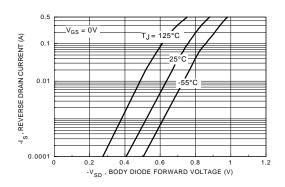


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Contact us: sales@integrated-circuit.com Website: www.integrated-circuit.com

Typical Electrical And Thermal Characteristics

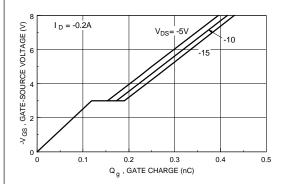


Figure 7. Gate Charge Characteristics.

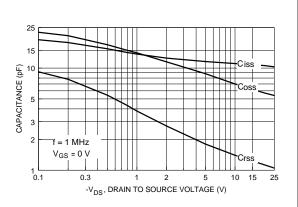


Figure 8. Capacitance Characteristics.

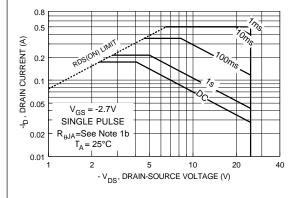


Figure 9. Maximum Safe Operating Area.

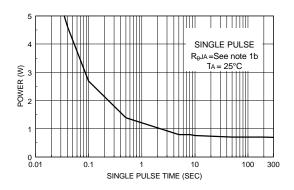


Figure 10. Single Pulse Maximum Power Dissipation.

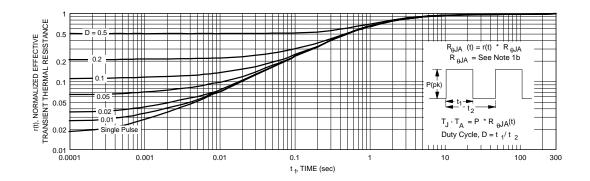


Figure 11. Transient Thermal Response Curve.

Note: Thermal characterization performed using the conditions described in note 1b.Transient thermal response will change depending on the circuit board design.



Distributor of Fairchild Semiconductor: Excellent Integrated System Limited Datasheet of FDC6302P - MOSFET 2P-CH 25V 0.12A SSOT6

Contact us: sales@integrated-circuit.com Website: www.integrated-circuit.com

TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

 VCX^{TM} SMART START™ FAST ® $ACEx^{TM}$ OPTOLOGIC™ FASTr™ STAR*POWER™ Bottomless™ OPTOPLANAR™ Stealth™ $\mathsf{CoolFET^{\scriptscriptstyle\mathsf{TM}}}$ FRFET™ PACMAN™ $CROSSVOLT^{\rm TM}$ РОР™ SuperSOT™-3 GlobalOptoisolator™ SuperSOT™-6 DenseTrench™ GTO™ Power247™ SuperSOT™-8 DOME™ HiSeC™ PowerTrench® SyncFET™ ISOPLANAR™ EcoSPARK™ **QFET™** E^2CMOS^{TM} TinyLogic[™] QSTM LittleFET™ $MicroFET^{TM}$ TruTranslation™ EnSigna™ QT Optoelectronics™ **UHC**TM MicroPak™ FACT™ Quiet Series™ UltraFET® FACT Quiet Series™ MICROWIRE™ SILENT SWITCHER®

STAR*POWER is used under license

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used berein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

| Datasheet Identification | Product Status | Definition |
|--------------------------|---------------------------|---|
| Advance Information | Formative or In Design | This datasheet contains the design specifications for product development. Specifications may change in any manner without notice. |
| Preliminary | First Production | This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design. |
| No Identification Needed | Full Production | This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design. |
| Obsolete | Not In Production | This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only. |

Rev. H4